

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re the Application of

Inventors: Osamu ICHIKAWA

Application No.: New Patent Application

Filed: August 26, 2003

For: SEMICONDUCTOR INTEGRATED CIRCUIT AND MEMORY TEST  
METHOD

INFORMATION DISCLOSURE STATEMENT

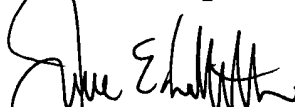
Honorable Commissioner of  
Patents and Trademarks  
Washington, DC 20231

Sir:

Pursuant to Rules 56 and 99, Applicants hereby call the attention of the Patent Office to the reference(s) listed on the attached Form PTO 1449.

Applicants present this art so that the Patent Office may, in the first instance, determine any relevancy thereof to the presently claimed invention, see Beckman Instruments, Inc. v. Chemtronics, Inc., 439 F.2d 1369, 1380, 165 USPQ 355, 364 (5th Cir. 1970). Also see Patent Office Rules 104 and 106. Applicants respectfully request that this art be expressly considered during the prosecution of this application and made of record herein and appear among the "References Cited" on any patent to issue herefrom.

Respectfully submitted,



James E. Ledbetter

Registration No. 28,732

Date: August 26, 2003

JEL/apg  
ATTORNEY DOCKET NO. L8462.03109  
STEVENS, DAVIS, MILLER & MOSHER, L.L.P.  
1615 L Street, NW, Suite 850  
P.O. Box 34387  
Washington, DC 20043-4387  
Telephone: (202) 785-0100  
Facsimile: (202) 408-5200

FORM PTO-1449 U.S. Department of Commerce  
(Rev. 4/92) Patent and Trademark Office

# INFORMATION DISCLOSURE STATEMENT BY APPLICANT

(Use several sheets if necessary)

ATTY. DOCKET NO.

L8462.03109

SERIAL NO.

Unassigned

APPLICANT

Osamu ICHIKAWA

FILING DATE

August 26, 2003

GROUP

Unassigned

## U.S. PATENT DOCUMENTS

| EXAMINER<br>INITIAL | DOCUMENT NUMBER | DATE    | NAME             | CLASS | SUBCLASS | FILING DATE<br>IF<br>APPROPRIATE |
|---------------------|-----------------|---------|------------------|-------|----------|----------------------------------|
|                     | 5 4 5 3 9 9 3   | 09/1995 | Kitaguchi et al. |       |          |                                  |
|                     |                 |         |                  |       |          |                                  |
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## FOREIGN PATENT DOCUMENTS

| DOCUMENT NUMBER | DATE | COUNTRY | CLASS | SUBCLASS | TRANSLATION |
|-----------------|------|---------|-------|----------|-------------|
|                 |      |         |       |          | YES NO      |
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## OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, Etc.)

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EXAMINER

DATE CONSIDERED

EXAMINER: Initial if citation is considered, draw line through citation if not in compliance and not considered. Include copy of this form with next communication to applicant.